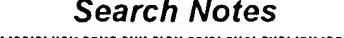


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/640,558	VAN DUYN, PAUL D.
	Examiner	Art Unit
	Jacob Y. Choi	2875

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
ALL	ALL	11/22/2005	JC